

Notice of References Cited	Application/Control No. 10/594,543		Applicant(s)/Patent Under Reexamination YAMAGIWA, AKIO	
	Examiner ALEX W. MOK		Art Unit 2834	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,729,102 A	03-1998	Gotou et al.	318/400.13
*	B	US-2003/0123178 A1	07-2003	Gotou et al.	360/73.03
*	C	US-2003/0107348 A1	06-2003	Inagawa et al.	322/22
*	D	US-6,630,764 B1	10-2003	Dube et al.	310/177
*	E	US-6,208,055 B1	03-2001	Takahashi, Osamu	310/156.01
*	F	US-4,724,350 A	02-1988	Shiraki et al.	310/268
*	G	US-6,005,324 A	12-1999	Kim, Hyung-Cheol	310/268
*	H	US-4,658,162 A	04-1987	Koyama et al.	310/68R
*	I	US-2003/0052553 A1	03-2003	Isozaki et al.	310/49.00R
*	J	US-5,581,422 A	12-1996	Umehara, Teruo	360/97.01
*	K	US-4,605,874 A	08-1986	Whiteley, Eric	310/268
*	L	US-5,679,990	10-1997	Ushiro, Tatsuzo	310/68B
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06022526 A	01-1994	Japan	HASHIMOTO, TOSHIO	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.